Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/667,316	HAYASHI ET AL.	
Examiner	Art Unit	
Anh T.N. Vo	2861	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMF	
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